
Identification cards — Test methods —

Part 6:

Proximity cards

**AMENDMENT 4: Additional test methods for
PCD RF interface and PICC alternating field
exposure**

Cartes d'identification — Méthodes d'essai —

Partie 6: Cartes de proximité

*AMENDEMENT 4: Méthodes d'essai additionnelles pour l'interface RF
des PCD et l'exposition des PICC au champ alternatif*

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Foreword

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International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

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Amendment 4 to ISO/IEC 10373-6:2001 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

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Part 6: Proximity cards

AMENDMENT 4: Additional test methods for PCD RF interface and PICC alternating field exposure

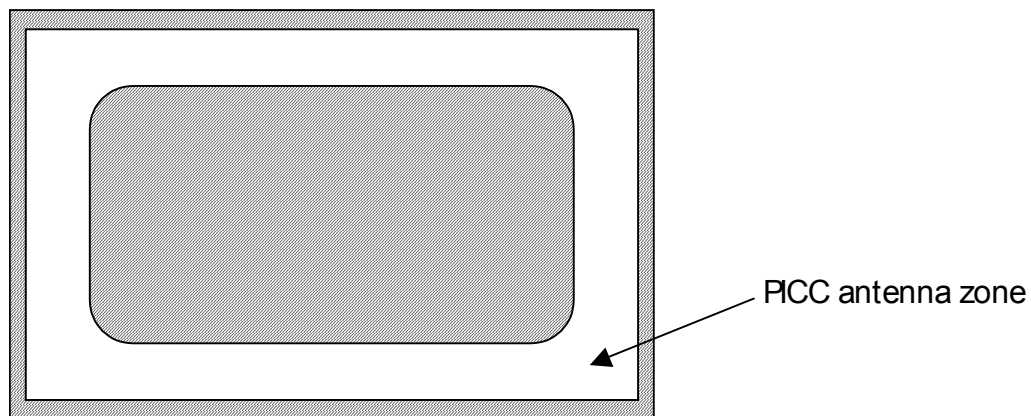
Page 2, 3.1.2

Replace the term, definition and associated footnote with the following:

"Class 1 PICC

PICC whose antenna is located within a zone defined by two rectangles:

- external rectangle: 81 mm × 49 mm;
- internal rectangle: 64 mm × 34 mm, centred in the external rectangle, with 3 mm radius, except for its connection endings.



WARNING — The "Class 1" PICC shall also pass the "Class 1" PICC maximum loading effect test defined in 7.4."